Addressing High Frequency Challenges for Burn-in Requiring LVDS

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BiTS Workshop March 5 - 8, 2017



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Introduction

- LVDS = Low Voltage Differential Signaling
- It is also known as TIA/EIA-644, a standard entitled "Electrical Characteristics of Low Voltage Differential Signaling (LVDS) Interface Circuits"
 - ❖ TIA = Telecommunication Industry Association
 - ❖ EIA = Electronic Industries Alliance



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Introduction

 LVDS is a low voltage, low power, differential technology used primarily for point-to-point and multi-drop driving applications



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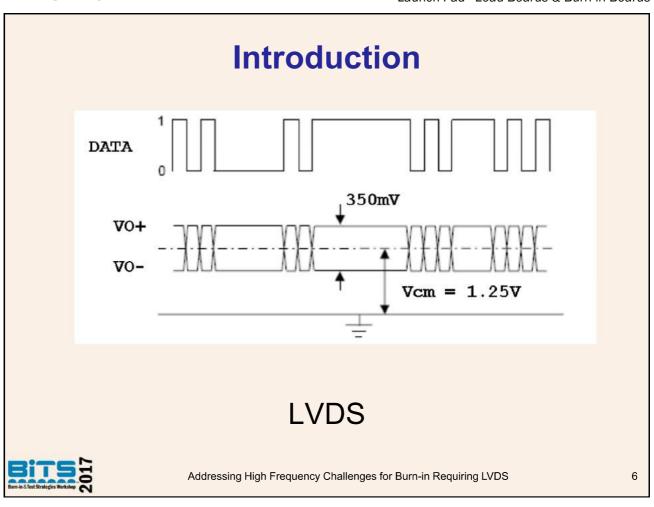
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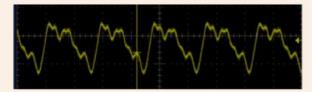


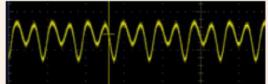
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Introduction





Sample scope shots of 27 MHz single-ended signals captured on burn-in boards

- Harmonic Distortion
- Doubled Frequency
- Attenuation beyond 100 MHz



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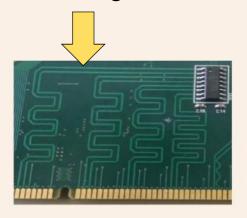
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Addressing Various LVDS Issues

- LVDS, a pair of PCB traces
 - 1) Differential traces should be as close as possible after leaving the driver output





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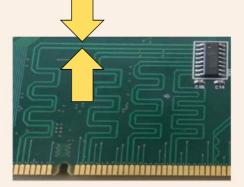
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Addressing Various LVDS Issues

LVDS, a pair of PCB traces

2) Distances between differential LVDS signals should remain constant on the entire length of the

traces

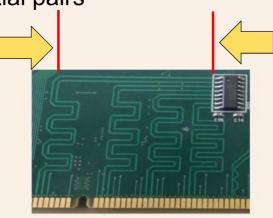




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Addressing Various LVDS Issues

- LVDS, a pair of PCB traces
 - 3) Electrical lengths should be the same between differential pairs





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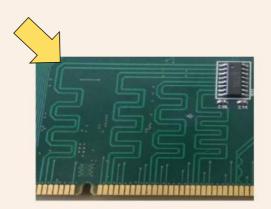
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Addressing Various LVDS Issues

- LVDS, a pair of PCB traces
 - 4) Arcs or 45° traces for each turn of traces





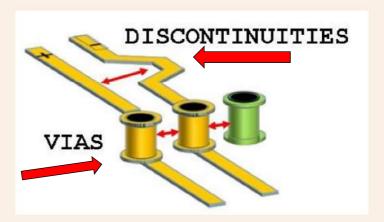
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Addressing Various LVDS Issues

- LVDS, a pair of PCB traces
 - 5) Minimize number of vias and other discontinuities





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Addressing Various LVDS Issues

- LVDS, a pair of PCB traces
 - 6) Parasitic loading (e.g. capacitance) must be present in equal amounts to each line



"Symmetry is KEY"



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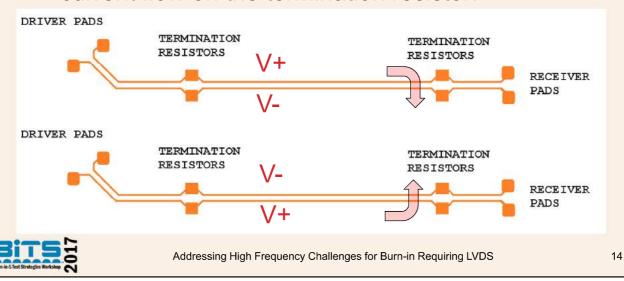
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Addressing Various LVDS Issues

Electromagnetic Interference

When the driver switches from logic high to logic low or vice versa, it changes the direction of current flow on the termination resistor.



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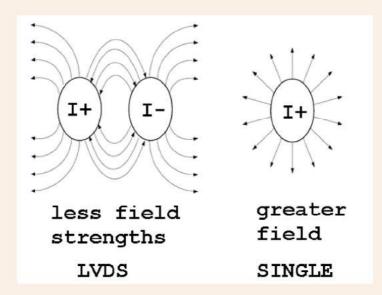
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Addressing Various LVDS Issues

Electromagnetic Interference (EMI)

LVDS generates lesser EMI





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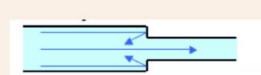
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Addressing Various LVDS Issues

Impedance Matching



Good Impedance Matching



With reflection

Improper Impedance Matching



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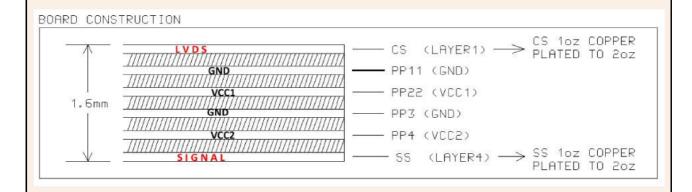
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Addressing Various LVDS Issues

Crosstalk

To isolate LVDS signal layers from single-ended, POWER and GND planes are placed in between





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Addressing Various LVDS Issues

High Temperature Deration

LVDS drivers are outside the hot zone chamber area



Power Supply

High Speed Clock Card

LVDS Module



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Design of Experiments

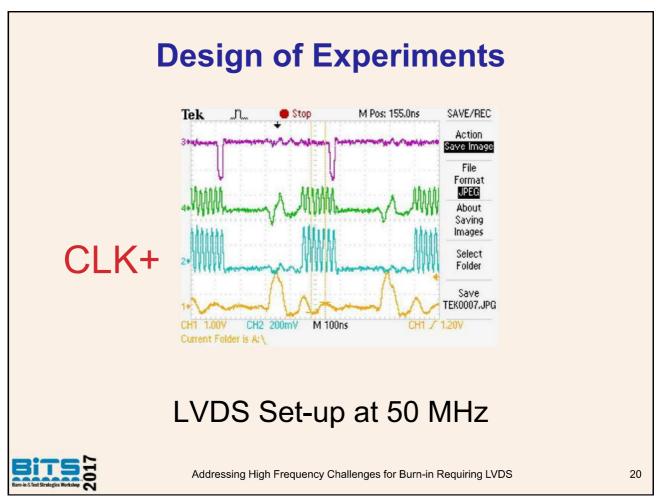
Objective:

 Check what is the maximum frequency that the LVDS set-up can generate



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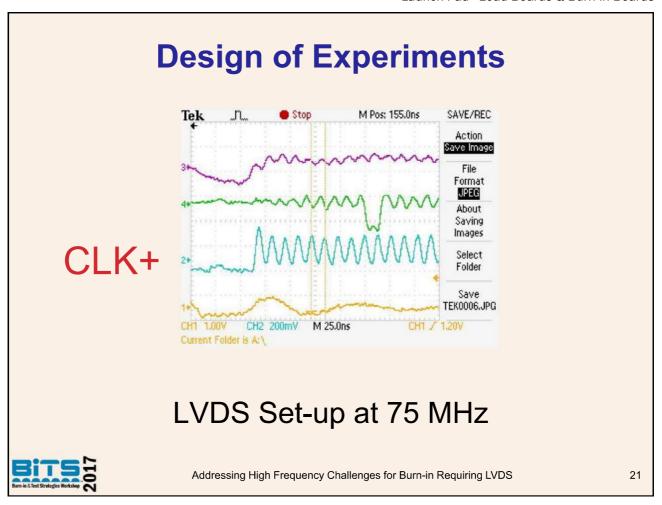


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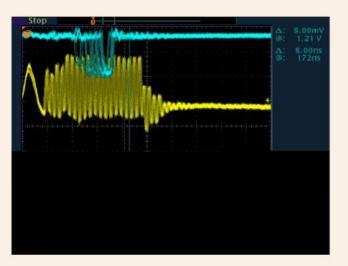
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Design of Experiments

CLK+



LVDS Set-up at 125 MHz



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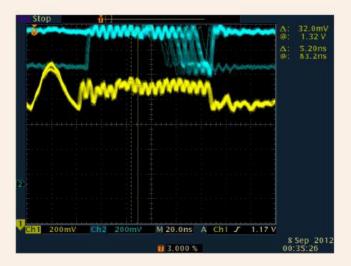
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Design of Experiments

CLK+



LVDS Set-up at 200 MHz



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Results and Discussion

1678	Set-up Remarks
Frequency	
50Mhz	Passed
75Mhz	Passed
120Mhz	Passed
200Mhz	Frequency acquired but the
	levels are degraded

The LVDS Set-up can generate up to 200 MHz but the highest frequency achieved with good signal integrity is 120 MHz.



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Recommendation

To achieve better results:

- 1) Further board developments
- 2) PCB CAD simulations
- 3) Bench Tests and Experiments
- 4) High RF Capability of Instruments
- 5) Avoid Edge Finger connections: Use high temp coax cables



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Acknowledgement

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- Eric Escalante, RF PCB Design Engineer, for the guidelines and support to RF and LVDS designs.



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